- Latched Data Inputs Serve as Buffer Register and Can also:
 - Synchronize Data Acquisition "Debounce" Mechanical Switch Input
- Cascading Input P0 and Output P1 Provides "Busy"Signal Inhibiting All Lower-Order Bits
- Full TTL Compatibility
- Use for:

Priority Interrupt
Synchronous Priority Line Selection

description

The SN54278 and SN74278 each consist of four data latches, full priority output gating, and a cascading gate. The highest-order data applied at a D latch input is transferred to the appropriate Y output while the strobe input is high, and when the strobe goes low all data is latched. The cascading input P0 is fully overriding and on the highest-order package this input must be held at a low logic level. The P1 output is intended for connection to the P0 input of the next lower-order package and will provide a "busy" (high-level) signal to inhibit all subsequent lower-order packages.

After the overriding P0 input, the order of priority is D1, D2, D3, and D4, respectively, within the package.

SN54278 . . . J OR W PACKAGE SN74278 . . . N PACKAGE (TOP VIEW)

J14□ Vcc STRB Π_1 D3 **1**2 D2 D4 **3** 12 D1 P0 Π_4 11 NC P1 **1**5 10 Y1 **Y4** 9[] Y2 □6 **GND Y3**

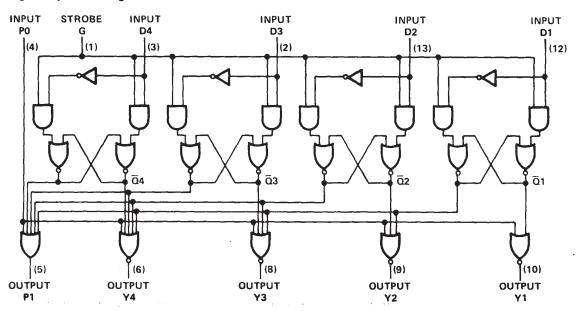
NC-No internal connection

FUNCTION TABLE

INPUTS						11	NTE	RNA	L	OUTPUTS							
						LA	тсн	NO	DES	0017018							
P0	G	D1	D2	D3	D4	Q1	Q2	ŌЗ	Q4	Y1	Y2	Y3	Y4	P1			
L	Н	Н	Х	Х	Х	L	X	X	Х	Н	L	L	L	н			
L	Н	L	Н	X	Х	Н	L	X	Х	L	Н	L	L	н			
L	Н	L	L	Н	Х	Н	Н	L	Х	L	L	Н	L	н			
L	Н	L	L	L	H	н	Н	Н	L	L	L	L	Н	н			
L	Н	L	L	L	L	Н	Н	<u>H</u>	Н	L	L	L	L	L			
										Same function of Q							
L	L	X	X	Х	Х	La	tche	d wh	en	nodes as on 1st							
						G	goes	low		51	ines			ļ			
Н	L	Х	X	Х	Х					٦	L	L	L	H			
Internal Q levels are same																	
Н	H H function of D inputs as on									L	L	L	L	н			
first 5 lines																	

H = high level, L = low level, X = irrelevant

logic diagram (positive logic)



TEXAS INSTRUMENTS

SDLS092 - NOVEMBER 1971 - REVIESED MARCH 1988

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V _{CC} (see Note 1) .																					7 \	/
Input voltage																					5.5 \	/
Interemitter voltage (see Note 2)																					5.5 \	/
Operating free-air temperature range:	 SN	54	127	78	Ci	rcı	iits	;									- 5	5°	C 1	to	125°(3
	SN	74	127	78	Ci	rcı	uits	;										0)°C	; to	70°C	
Storage temperature range																	-6	i5°	C 1	to	150°(3

NOTES: 1. Voltage values, except interemitter voltage, are with respect to network ground terminal.

2. This is the voltage between two emitters of a multiple-emitter transistor. For this circuit, this rating applies between the strobe input and any of the four data inputs.

recommended operating conditions

	s	N5427	8	S	UNIT		
	MIN	NOM	MAX	MIN	NOM	MAX	ONT
Supply voltage, VCC	4.5	5	5.5	4.75	5	5.25	V
High-level output current, IOH			-800			-800	μΑ
Low-level output current, IOL			16			16	mA
Data setup time, t _{SU} (see Figure 1)	20			20			ns
Data hold time, th (see Figure 1)	5			5			ns
Strobe pulse width, t _W (see Figure 1)	20			20			ns
Operating free-air temperature, TA	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

-	PARAMETER		TEST CO	NDITIONS†	MIN	TYP	MAX	UNIT
VIH	High-level input voltage				2			٧
VIL	Low-level input voltage						0.8	٧
VIK	Input clamp voltage		V _{CC} = MIN,	1 ₁ = -12 mA			-1.5	٧
VoH	High-level output voltage		V _{CC} = MIN, V _{IL} = 0.8 V,	V _{IH} = 2 V, I _{OH} = -800 μA	2.4	3.4		٧
VOL	Low-level output voltage		V _{CC} = MIN, V _{IL} = 0.8 V,	V _{IH} = 2 V, I _{OL} = 16 mA		0.2	0.4	٧
11	Input current at maximum input volta	age	V _{CC} = MAX,	V ₁ = 5.5 V			1	mΑ
•		Any D input					80	
Ιн	High-level input current	P0 input	V _{CC} = MAX,	V ₁ = 2.4 V			200	μΑ
***		G input					320	
		Any D input					-3.2	
IJЦ	Low-level input current	P0 input	V _{CC} = MAX,	V _I = 0.4 V			8	mA
		G input					-12.8	
			VMAY	SN54278	-18		-55	mA
los	Short-circuit output current §		V _{CC} = MAX	SN74278	-18		-57] ""^
Icc	Supply current		V _{CC} = MAX,	See Note 3		55	80	mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.

NOTE 3: ICC is measured with the P0 input grounded, all other inputs at 4,5 V, and outputs open.



[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

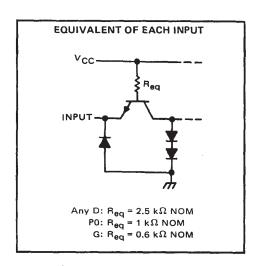
[§] Not more than one output should be shorted at a time.

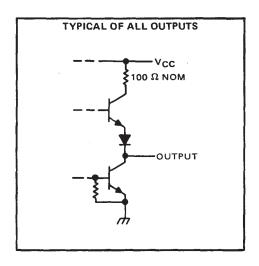
switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ} \text{C}$

PARAMETER†	FROM (INPUT)	TO (OUTPUT)	WAVEFORMS	TEST CONDITIONS	MIN TYP MA	UNIT
tPLH	Data	Y	A and C		30	
^t PHL	Data	'	(with strobe high)		39	ns
tPLH .	Data	Y	A and D	7	38	
^t PHL	Data	T T	(with strobe high)		31	ns
tPLH .	Data	P1	A and E	0 15 - 5	46	
tPHL	Data	r i	(with strobe high)	CL = 15 pF,	39	ns
tPLH	Strobe	Any Y	B and C	R _L = 400 Ω, See Figure 1	30	
t _{PHL}	Strobe	Any t	or B and D	See Figure 1	31	ns
tPLH .	Strobe	P1	D and E	1	38	
tPHL	Strobe	F 1	B and E		42	ns
tPLH .	PO	P1	F 4 C		23	
tPHL	ru	PI	F and G		30	ns

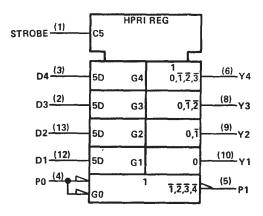
 $^{^{\}dagger} t_{PLH} = propagation delay time, low-to-high-level output$

schematics of inputs and outputs





logic symbol†

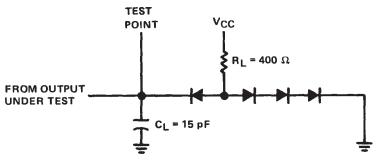


[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



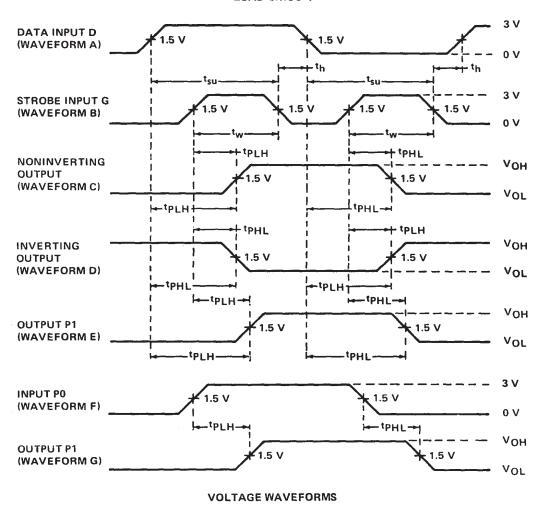
tpHL = propagation delay time, high-to-low-level output

PARAMETER MEASUREMENT INFORMATION



 C_L includes probe and jig capacitance. All diodes are 1N3064.

LOAD CIRCUIT



NOTE: Input pulses are supplied by a generator having the following characteristics: $t_r \le 7$ ns, $t_f \le 7$ ns, PRR \le MHz, $Z_{out} \approx 50\Omega$.

FIGURE 1-SWITCHING TIMES



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